

International Congress of Metrology, Paris, October 8th, 2013

EMRP IND07 (Thin Films) and NEW01 (TReND)

“Reliable characterization methodologies for advanced materials”

Workshop Agenda

Opening: M. Chambon (LNE) 11:35-11:40
Chairs: B. Beckhoff (PTB) and M.-C. Lépy (LNHB) 11:40-11:50

Melissa Passerelli, NPL, UK 11:50-12:15
Metrology for 3D secondary ion mass spectrometry imaging

Daniel Abou-Ras, HZB, Germany 12:15-12:40
Comprehensive Comparison of Various Techniques for the Analysis of Elemental Distributions in Thin Films.

Emmanuel Nolot, LETI, France 12:40-13:05
State-of-the-art physical and chemical characterization for the nanoelectronic industry

LUNCH BREAK

Claudia Fleischmann, IMEC, Belgium 14:00-14:25
Soft x-ray spectroscopy for the analysis of advanced (opto)electronic materials

Andreas Hertwig, BAM, Germany 14:25-14:50
Accurate determination of film thicknesses and optical constants with ellipsometry

Peter Petrik, MFA, Hungary 14:50-15:15
Optical mapping and depth profiling using polarized light

Petr Klapetek, CMI, Czech Republic 15:15-15:40
Towards quantitative scanning probe microscopy

Andreas Nutsch, PTB, Germany 15:40-16:00
Characterisation of Materials for Nanotechnology and Life Science using soft X-Ray's at PTB's Synchrotron Facilities

General discussion and conclusion 16:00 – 16:30

EMRP



- EMRP supports the collaboration of European metrology institutes, industrial organisations and academia through Joint Research Projects (JRPs). It is structured around European Grand Challenges in such areas as Health, Energy, the Environment & New Technologies
- This presentation is one of 17 presentations, 5 posters and 2 workshops at this conference supported by the European Metrology Programme, implemented by EURAMET.
- The last call for EMRP proposals has just closed – but we look forward to its successor - EMPiR. See www.euramet.org for more details



SI Units (2011 & 2012)



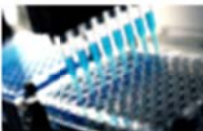
Environment (2010 & 2013)



Energy (2009 & 2013)



New Technologies (2011)



Health (2011)



Industry (2010 & 2012)